

Appl. No.:
Amdt. dated: September 10, 2003
Preliminary Amendment

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claim 1 (canceled):

Claim 2 (new): A method of testing a device under test comprising:

- (a) providing a beam of light from a light source having a first wavelength;
- (b) imposing said beam of light on a test device over a spatial region within said test device substantially greater than said first wavelength, wherein said test device has a first state;
- (c) imposing said beam of light on said test device over a spatial region within said test device substantially greater than said first wavelength, wherein said test device has a second state;
- (d) obtaining data resulting from the interference of said first beam and said second beam within said device under test representative of the voltages within said region;
- (e) wherein said first state is at a first voltage potential, and wherein said second state is at a second voltage potential different from said first voltage potential.